Notice of References Cited Application/Control No. 10/777,134 Examiner Christopher B. Shin Applicant(s)/Patent Under Reexamination HAYAMIZU ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,576,706	11-1996	Daigle et al.	341/22
*	В	US-5,936,614	08-1999	An et al.	345/173
*	С	US-6,121,960	09-2000	Carroll et al.	345/173
*	D	US-4,587,630	05-1986	Straton et al.	715/823
*	Е	US-5,724,069	03-1998	Chen, Jack Y.	345/172
*	F	US-6,491,630	12-2002	Saccardo et al.	600/437
*	G	US-2004/0243314	12-2004	Cohen et al.	702/019
*	Н	US-5,297,031	03-1994	Gutterman et al.	705/37
*	1	US-5,818,451	10-1998	Bertram et al.	715/840
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	•				
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	V	
	W	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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